



Silicon Wafer Japan TC Chapter Meeting

Japan Standards Summer Meetings 2026

Friday, August 28, 2026

Board Room, SEMI Japan, Tokyo, Japan/ Official Virtual TC Chapter Meeting (Hybrid)

1:00 PM — 4:00 PM JST

AGENDA

1 Welcome/Call to Order

- 1.1 Introductions
- 1.2 Required Meeting Elements
- 1.3 Agenda Review

2 Review of Previous Meeting Minutes

3 Liaison Report

- 3.1 Japan Regional Standards Committee (JRSC)
- 3.2 Global Coordinating Subcommittee (GCS)
- 3.3 Europe TC Chapter
- 3.4 North America TC Chapter

4 Staff Report

5 Ballot Review

- 5.1 Doc.#7468, Revision to SEMI M95-0925, Test Method for Net Carrier Density and Resistivity of Silicon Epitaxial Layer by Capacitance Voltage Measurements with an Evaporated Metal Schottky Diode

6 Subcommittee & Task Force Reports

- 6.1 International Advanced Wafer Geometry Task Force
- 6.2 International/ Japan Test Method Task Force
- 6.3 International Advanced Surface Inspection Task Force
- 6.4 International Polished Wafers Task Force
- 6.5 International Epitaxial Wafers Task Force

6.6 International Annealed Wafers Task Force

6.7 International SOI Wafers Task Force

6.8 International Terminology Task Force

7 Old Business

7.1 Project Period Review

- SNARF 6687, Revision of M51, Test Method for Characterizing Silicon Wafer by Gate Oxide Integrity (extension expires on 2026/10/02)

7.2 5-year Review

8 New Business

8.1 SNARF for Line Item Revision to SEMI M90-0821, Test Method for Bulk Micro Defect Density and Denuded Zone Width in Annealed Silicon Wafers by Optical Microscopy After Preferential Etching

9 Action Item Review

9.1 Open Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
SW20260417-01	SEMI Staff	To forward the ballot adjudication results of Doc.#6570D to the ISC A&R SC for procedural review.
SW20260417-02	Ryuji Takeda	To bring up the Int'l Terminology TF co-leader absence issue to the Silicon Wafer GCS.
SW20260417-03	SEMI Staff	To prepare SNARFs for Line Item Revision to SEMI M67 and M68.
SW20251218-04	SEMI Staff	To send SEMI M95 Major Revision SNARF for two weeks review from the global Silicon Wafer TC members.

9.2 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>

10 Next Meeting and Adjournment

10.1 The next meeting is scheduled for <date> at <event/location>.